

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/050,002	PAVIER, MARK	
Examiner		Art Unit		Page 1 of 1
Chris C. Chu		2815		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6353265 - B1	03-2002	Michii	257/777
	B	US-6344687 - B1	02-2002	Huang et al.	257/724
	C	US-6313527 - B1	11-2001	Han et al.	257/723
	D	US-6175149 - B1	01-2001	Akram	257/676
	E	US-6133067 - A	10-2000	Jeng et al.	438/110
	F	US-5793108 - A	08-1998	Nakanishi et al.	257/723
	G	US-5719436 - A	02-1998	Kuhn	257/676
	H	US-5625226 - A	04-1997	Kinzer	257/705
	I	US-5596225 - A	01-1997	Mathew et al.	257/667
	J	US-5147815 - A	09-1992	Casto	29/827
	K	US-4993148 - A	02-1991	Adachi et al.	29/832
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP - 11317488 - A	11-1999	Japan	Inaba et al.	---
	O	JP - 10256470 - A	09-1998	Japan	Tsubonoya	---
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
	U	
	V	
	W	
	X	

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